Microchip Technology - A40MX04-VQG80A Datasheet

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Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	69
Number of Gates	6000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 125°C (TA)
Package / Case	80-TQFP
Supplier Device Package	80-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx04-vqg80a

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Table 1 • **Product profile**

Device	**A40MX02**	**A40MX04**	**A42MX09**	**A42MX16**	**A42MX24**	**A42MX36**
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	–	–	–	–	Yes	Yes
Boundary Scan Test (BST)	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–

3 40MX and 42MX FPGAs

3.1 General Description

Microsemi's 40MX and 42MX families offer a cost-effective design solution at 5V. The MX devices are single-chip solutions and provide high performance while shortening the system design and development cycle. MX devices can integrate and consolidate logic implemented in multiple PALs, CPLDs, and FPGAs. Example applications include high-speed controllers and address decoding, peripheral bus interfaces, DSP, and co-processor functions.

The MX device architecture is based on Microsemi’s patented antifuse technology implemented in a 0.45µm triple-metal CMOS process. With capacities ranging from 3,000 to 54,000 system gates, the MX devices provide performance up to 250 MHz, are live on power-up and have one-fifth the standby power consumption of comparable FPGAs. MX FPGAs provide up to 202 user I/Os and are available in a wide variety of packages and speed grades.

A42MX24 and A42MX36 devices also feature multiPlex I/Os, which support mixed-voltage systems, enable programmable PCI, deliver high-performance operation at both 5.0V and 3.3V, and provide a low-power mode. The devices are fully compliant with the PCI local bus specification (version 2.1). They deliver 200 MHz on-chip operation and 6.1 ns clock-to-output performance.

The 42MX24 and 42MX36 devices include system-level features such as IEEE Standard 1149.1 (JTAG) Boundary Scan Testing and fast wide-decode modules. In addition, the A42MX36 device offers dual-port SRAM for implementing fast FIFOs, LIFOs, and temporary data storage. The storage elements can efficiently address applications requiring wide data path manipulation and can perform transformation functions such as those required for telecommunications, networking, and DSP.

All MX devices are fully tested over automotive and military temperature ranges. In addition, the largest member of the family, the A42MX36, is available in both CQ208 and CQ256 ceramic packages screened to MIL-STD-883 levels. For easy prototyping and conversion from plastic to ceramic, the CQ208 and PQ208 devices are pin-compatible.

3.2 MX Architectural Overview

The MX devices are composed of fine-grained building blocks that enable fast, efficient logic designs. All devices within these families are composed of logic modules, I/O modules, routing resources and clock networks, which are the building blocks for fast logic designs. In addition, the A42MX36 device contains embedded dual-port SRAM modules, which are optimized for high-speed data path functions such as FIFOs, LIFOs and scratch pad memory. A42MX24 and A42MX36 also contain wide-decode modules.

3.2.1 Logic Modules

The 40MX logic module is an eight-input, one-output logic circuit designed to implement a wide range of logic functions with efficient use of interconnect routing resources.(see the following figure).

The logic module can implement the four basic logic functions (NAND, AND, OR and NOR) in gates of two, three, or four inputs. The logic module can also implement a variety of D-latches, exclusivity functions, AND-ORs and OR-ANDs. No dedicated hard-wired latches or flip-flops are required in the array; latches and flip-flops can be constructed from logic modules whenever required in the application.

Figure 5 • **A42MX24 and A42MX36 D-Module Implementation**

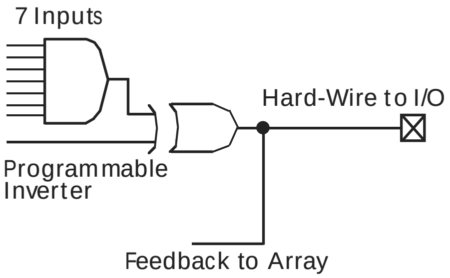
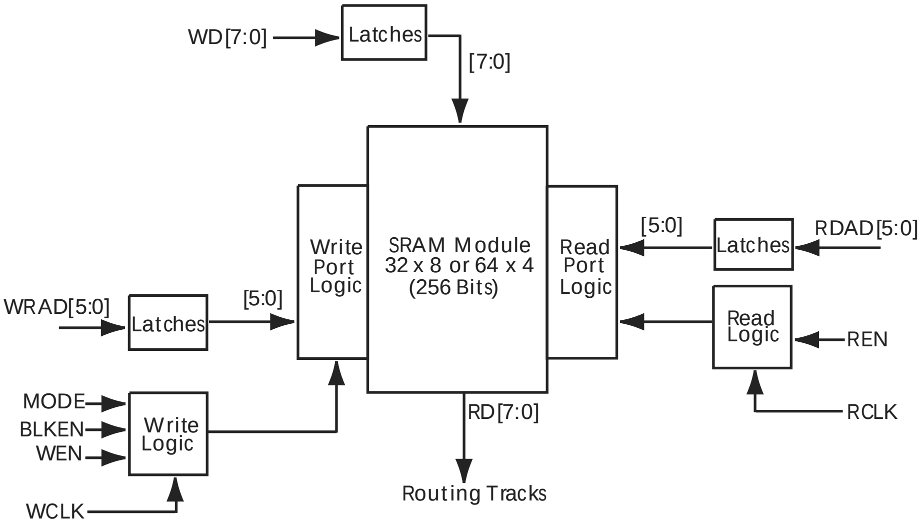


Figure 6 • **A42MX36 Dual-Port SRAM Block**



3.2.3 Routing Structure

The MX architecture uses vertical and horizontal routing tracks to interconnect the various logic and I/O modules. These routing tracks are metal interconnects that may be continuous or split into segments. Varying segment lengths allow the interconnect of over 90% of design tracks to occur with only two antifuse connections. Segments can be joined together at the ends using antifuses to increase their lengths up to the full length of the track. All interconnects can be accomplished with a maximum of four antifuses.

3.2.3.1 Horizontal Routing

Horizontal routing tracks span the whole row length or are divided into multiple segments and are located in between the rows of modules. Any segment that spans more than one-third of the row length is considered a long horizontal segment. A typical channel is shown in Figure 7, page 10. Within horizontal routing, dedicated routing tracks are used for global clock networks and for power and ground tie-off tracks. Non-dedicated tracks are used for signal nets.

3.2.3.2 Vertical Routing

Another set of routing tracks run vertically through the module. There are three types of vertical tracks: input, output, and long. Long tracks span the column length of the module, and can be divided into multiple segments. Each segment in an input track is dedicated to the input of a particular module; each segment in an output track is dedicated to the output of a particular module. Long segments are uncommitted and can be assigned during routing.

Each output segment spans four channels (two above and two below), except near the top and bottom of the array, where edge effects occur. Long vertical tracks contain either one or two segments. An example of vertical routing tracks and segments is shown in Figure 7, page 10.

Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • **Voltage Support of MX Devices**

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max}\cdot\text{junction}\ \ \text{temp}\cdot(°\text{C}) - \text{Max}\cdot\text{ambient}\ \ \text{temp}\cdot(°\text{C})}{\theta_{ja}(°\text{C}/\text{W}))} = \frac{150°\text{C} - 70°\text{C}}{(28°\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

The maximum power dissipation for military-grade devices is a function of θ_{jc}. A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max}\cdot\text{junction}\ \ \text{temp}\cdot(°\text{C}) - \text{Max}\cdot\text{ambient}\ \ \text{temp}\cdot(°\text{C})}{\theta_{jc}(°\text{C}/\text{W}))} = \frac{150°\text{C} - 125°\text{C}}{(6.3°\text{C})/\text{W}} = 3.97\text{W}$$

EQ 6

Table 27 • **Package Thermal Characteristics**

			θ_{ja}			
Plastic Packages	**Pin Count**	θ_{jc}	**Still Air**	**1.0 m/s 200 ft/min.**	**2.5 m/s 500 ft/min.**	**Units**
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	°C/W
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	°C/W
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	°C/W
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	°C/W
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	°C/W
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	°C/W
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	°C/W
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	°C/W
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	°C/W
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	°C/W
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	°C/W
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	°C/W
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	°C/W

approximately a 3 ns to a 6 ns delay, which is represented statistically in higher fanout (FO=8) routing delays in the data sheet specifications section, shown in Table 34, page 41.

3.11.3 Timing Derating

MX devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature and worst-case processing.

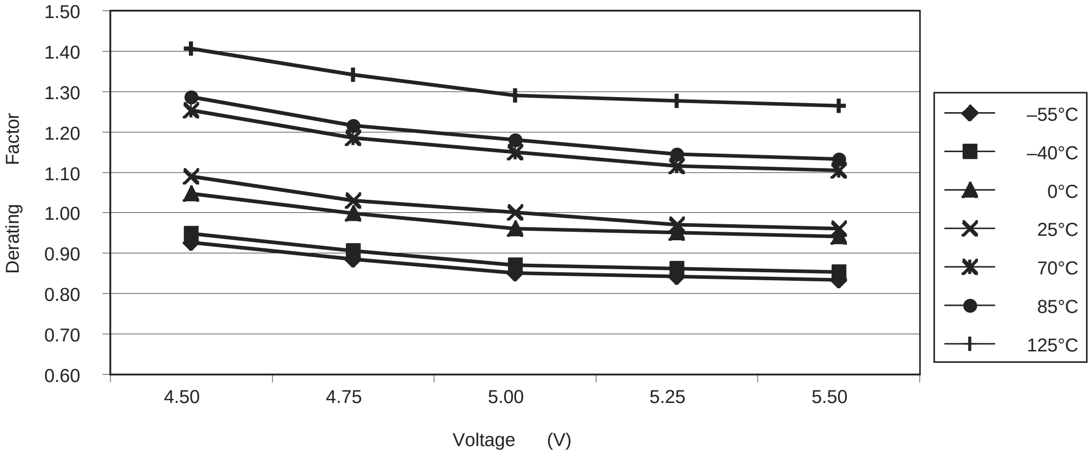
3.11.4 Temperature and Voltage Derating Factors

The following tables and figures show temperature and voltage derating factors for 40MX and 42MX FPGAs.

Table 28 • **42MX Temperature and Voltage Derating Factors (Normalized to T_J = 25°C, VCCA = 5.0 V)**

	Temperature						
42MX Voltage	**–55°C**	**–40°C**	**0°C**	**25°C**	**70°C**	**85°C**	**125°C**
4.50	0.93	0.95	1.05	1.09	1.25	1.29	1.41
4.75	0.88	0.90	1.00	1.03	1.18	1.22	1.34
5.00	0.85	0.87	0.96	1.00	1.15	1.18	1.29
5.25	0.84	0.86	0.95	0.97	1.12	1.14	1.28
5.50	0.83	0.85	0.94	0.96	1.10	1.13	1.26

Figure 34 • **42MX Junction Temperature and Voltage Derating Curves (Normalized to TJ = 25°C, VCCA = 5.0 V)**



Note: This derating factor applies to all routing and propagation delays

Table 29 • **40MX Temperature and Voltage Derating Factors(Normalized to TJ = 25°C, VCC = 5.0 V)**

	Temperature						
40MX Voltage	**–55°C**	**–40°C**	**0°C**	**25°C**	**70°C**	**85°C**	**125°C**
4.50	0.89	0.93	1.02	1.09	1.25	1.31	1.45
4.75	0.84	0.88	0.97	1.03	1.18	1.24	1.37
5.00	0.82	0.85	0.94	1.00	1.15	1.20	1.33
5.25	0.80	0.82	0.91	0.97	1.12	1.16	1.29
5.50	0.79	0.82	0.90	0.96	1.10	1.15	1.28

Table 38 • **A42MX09 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

		–3 Speed		**–2 Speed**		**–1 Speed**		**Std Speed**		**–F Speed**		
Parameter / Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
TTL Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		2.5		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{ENZH}	Enable Pad Z to HIGH		2.6		2.9		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t_{GLH}	G-to-Pad HIGH		2.6		2.9		3.3		3.8		5.3	ns
t_{GHL}	G-to-Pad LOW		2.6		2.9		3.3		3.8		5.3	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.04		0.04		0.04		0.05		0.07	ns/pF

Table 38 • **A42MX09 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		2.4		2.7		3.1		3.6		5.1	ns
t_{DHL}	Data-to-Pad LOW		2.9		3.2		3.6		4.3		6.0	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		2.9		3.3		3.9		5.5	ns
t_{ENZL}	Enable Pad Z to LOW		2.9		3.2		3.7		4.3		6.1	ns
t_{ENHZ}	Enable Pad HIGH to Z		4.9		5.4		6.2		7.3		10.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.3		5.9		6.7		7.9		11.1	ns
t_{GLH}	G-to-Pad HIGH		4.2		4.6		5.2		6.1		8.6	ns
t_{GHL}	G-to-Pad LOW		4.2		4.6		5.2		6.1		8.6	ns
t_{LSU}	I/O Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.2		5.8		6.6		7.7		10.8	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		7.4		8.2		9.3		10.9		15.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.04		0.04		0.04		0.05		0.07	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

Table 39 • **A42MX09 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.6		1.8		2.1		2.5		3.5	ns
t_{CO}	Sequential Clock-to-Q		1.8		2.0		2.3		2.7		3.8	ns
t_{GO}	Latch G-to-Q		1.7		1.9		2.1		2.5		3.5	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		2.0		2.2		2.5		2.9		4.1	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		1.0		1.1		1.2		1.4		2.0	ns
t_{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t_{RD3}	FO = 3 Routing Delay		1.6		1.8		2.0		2.4		3.3	ns

Table 41 • **A42MX16 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description			**–3 Speed**		**–2 Speed**		**–1 Speed**		**Std Speed**		**–F Speed**		
			Min.	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Logic Module Sequential Timing[3, 4]													
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.5		0.5		0.6		0.7		0.9		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up		1.0		1.1		1.2		1.4		2.0		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.8		5.3		6.0		7.1		9.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.9		9.2		12.9		ns
t_A	Flip-Flop Clock Input Period		9.5		10.6		12.0		14.1		19.8		ns
t_{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Buffer Latch Set-Up		0.7		0.8		0.9		1.01		1.4		ns
t_{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{OUTSU}	Output Buffer Latch Set-Up		0.7		0.8		0.89		1.01		1.4		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency			129		117		108		94		56	MHz
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			1.5		1.6		1.9		2.2		3.1	ns
t_{INYL}	Pad-to-Y LOW			1.1		1.3		1.4		1.7		2.4	ns
t_{INGH}	G to Y HIGH			2.0		2.2		2.5		2.9		4.1	ns
t_{INGL}	G to Y LOW			2.0		2.2		2.5		2.9		4.1	ns
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
t_{IRD2}	FO = 2 Routing Delay			2.9		3.2		3.7		4.3		6.1	ns
t_{IRD3}	FO = 3 Routing Delay			3.3		3.6		4.1		4.9		6.8	ns
t_{IRD4}	FO = 4 Routing Delay			3.6		4.0		4.6		5.4		7.6	ns
t_{IRD8}	FO = 8 Routing Delay			5.1		5.6		6.4		7.5		10.5	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32 FO = 384		4.4 4.8		4.8 5.3		5.5 6.0		6.5 7.1		9.0 9.9	ns ns
t_{CKL}	Input HIGH to LOW	FO = 32 FO = 384		5.3 6.2		5.9 6.9		6.7 7.9		7.8 9.2		11.0 12.9	ns ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 384	5.7 6.6		6.3 7.4		7.1 8.3		8.4 9.8		11.8 13.7		ns ns

Table 42 • **A42MX24 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Propagation Delays												
t_{INPY}	Input Data Pad-to-Y		1.0		1.1		1.3		1.5		2.1	ns
t_{INGO}	Input Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.6	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Latch Set-Up	0.5		0.5		0.6		0.7		1.0		ns
t_{ILA}	Latch Active Pulse Width	4.7		5.2		5.9		6.9		9.7		ns

Table 44 • **A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

		–3 Speed		**–2 Speed**		**–1 Speed**		**Std Speed**		**–F Speed**		
Parameter / Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Logic Module Combinatorial Functions[1]												
t_{PD}	Internal Array Module Delay		1.3		1.5		1.7		2.0		2.7	ns
t_{PDD}	Internal Decode Module Delay		1.6		1.8		2.0		2.4		3.3	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.2		1.4		2.0	ns
t_{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t_{RD3}	FO =3 Routing Delay		1.6		1.8		2.0		2.4		3.4	ns
t_{RD4}	FO = 4 Routing Delay		2.0		2.2		2.5		2.9		4.1	ns
t_{RD5}	FO = 8 Routing Delay		3.3		3.7		4.2		4.9		6.9	ns
t_{RDD}	Decode-to-Output Routing Delay		0.3		0.4		0.4		0.5		0.7	ns
Logic Module Sequential Timing[3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.3		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		1.6		1.7		2.0		2.3		3.2	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.5		6.4		9.0		ns
Synchronous SRAM Operations												
t_{RC}	Read Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{WC}	Write Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{RCKHL}	Clock HIGH/LOW Time	3.4		3.8		4.3		5.0		7.0		ns
t_{RCO}	Data Valid After Clock HIGH/LOW		3.4		3.8		4.3		5.0		7.0	ns
t_{ADSU}	Address/Data Set-Up Time	1.6		1.8		2.0		2.4		3.4		ns
Synchronous SRAM Operations (continued)												
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.6		0.7		0.8		0.9		1.3		ns
t_{RENH}	Read Enable Hold	3.4		3.8		4.3		5.0		7.0		ns
t_{WENSU}	Write Enable Set-Up	2.7		3.0		3.4		4.0		5.6		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	2.8		3.1		3.5		4.1		5.7		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/OTest Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/OTest Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/OTest Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10kΩ pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/OWide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
80	GNDI
81	NC
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	I/O
88	VKS
89	VPP
90	VCC
91	VCCI
92	NC
93	VSV
94	I/O
95	I/O
96	I/O
97	I/O
98	I/O
99	I/O
100	GND
101	GNDI
102	NC
103	I/O
104	I/O
105	I/O
106	I/O
107	I/O
108	I/O
109	I/O
110	SDI
111	I/O
112	I/O
113	I/O
114	I/O
115	I/O
116	GNDQ

Table 54 • **PQ240**

PQ240	
Pin Number	**A42MX36 Function**
163	WD, I/O
164	WD, I/O
165	I/O
166	QCLKA, I/O
167	I/O
168	I/O
169	I/O
170	I/O
171	I/O
172	VCCI
173	I/O
174	WD, I/O
175	WD, I/O
176	I/O
177	I/O
178	TDI, I/O
179	TMS, I/O
180	GND
181	VCCA
182	GND
183	I/O
184	I/O
185	I/O
186	I/O
187	I/O
188	I/O
189	I/O
190	I/O
191	I/O
192	VCCI
193	I/O
194	I/O
195	I/O
196	I/O
197	I/O
198	I/O
199	I/O

Table 57 • **TQ176**

TQ176			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	NC	VCCA	VCCA
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	GND	GND	GND
19	NC	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	NC	I/O	I/O
23	GND	GND	GND
24	NC	VCCI	VCCI
25	VCCA	VCCA	VCCA
26	NC	I/O	I/O
27	NC	I/O	I/O
28	VCCI	VCCA	VCCA
29	NC	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	NC	NC	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	NC	I/O	I/O
38	NC	NC	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	GND	GND	GND
46	I/O	I/O	TMS, I/O

Table 57 • **TQ176**

TQ176			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
84	I/O	I/O	WD, I/O
85	I/O	I/O	WD, I/O
86	NC	I/O	I/O
87	SDO, I/O	SDO, I/O	SDO, TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	I/O	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	NC	NC	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	GND	GND	GND
107	NC	I/O	I/O
108	NC	I/O	TCK, I/O
109	LP	LP	LP
110	VCCA	VCCA	VCCA
111	GND	GND	GND
112	VCCI	VCCI	VCCI
113	VCCA	VCCA	VCCA
114	NC	I/O	I/O
115	NC	I/O	I/O
116	NC	VCCA	VCCA
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O

Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
170	VCCA
171	I/O
172	I/O
173	I/O
174	I/O
175	I/O
176	I/O
177	I/O
178	I/O
179	I/O
180	GND
181	I/O
182	I/O
183	I/O
184	I/O
185	I/O
186	I/O
187	I/O
188	MODE
189	VCCA
190	GND
191	NC
192	NC
193	NC
194	I/O
195	DCLK, I/O
196	I/O
197	I/O
198	I/O
199	WD, I/O
200	WD, I/O
201	VCCI
202	I/O
203	I/O
204	I/O
205	I/O
206	GND

Table 59 • **CQ256**

CQ256	
Pin Number	**A42MX36 Function**
207	I/O
208	I/O
209	QCLKC, I/O
210	I/O
211	WD, I/O
212	WD, I/O
213	I/O
214	I/O
215	WD, I/O
216	WD, I/O
217	I/O
218	PRB, I/O
219	I/O
220	CLKB, I/O
221	I/O
222	GND
223	GND
224	VCCA
225	VCCI
226	I/O
227	CLKA, I/O
228	I/O
229	PRA, I/O
230	I/O
231	I/O
232	WD, I/O
233	WD, I/O
234	I/O
235	I/O
236	I/O
237	I/O
238	I/O
239	I/O
240	QCLKD, I/O
241	I/O
242	WD, I/O
243	GND

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
F2	I/O
F1	I/O
G1	I/O
G4	VSV
H1	I/O
H2	I/O
H3	I/O
H4	I/O
J1	I/O
K1	I/O
L1	I/O
K2	I/O
M1	I/O
K3	I/O
L2	I/O
N1	I/O
L3	BININ
M2	BINOUT
N2	I/O
M3	I/O
L4	I/O
N3	I/O
M4	I/O
N4	I/O
M5	I/O
K6	I/O
N5	I/O
N6	I/O
L6	I/O
M6	I/O
M7	I/O
N7	I/O
N8	I/O
M8	I/O
L8	I/O
K8	I/O
N9	I/O

Table 61 • **PG132**

PG132	
Pin Number	**A42MX09 Function**
G12	VSV
F13	I/O
F12	I/O
F11	I/O
F10	I/O
E13	I/O
D13	I/O
D12	I/O
C13	I/O
B13	I/O
D11	I/O
C12	I/O
A13	I/O
C11	I/O
B12	SDI
B11	I/O
C10	I/O
A12	I/O
A11	I/O
B10	I/O
D8	I/O
A10	I/O
C8	I/O
A9	I/O
B8	PRBA
A8	I/O
B7	CLKA
A7	I/O
B6	CLKB
A6	I/O
C6	PRBB
A5	I/O
D6	I/O
A4	I/O
B4	I/O
A3	I/O
C4	I/O